U.S. DEPARTMENT OF COMMERCE ATTY, DOCKET NO. SERIAL NO. Form PTO-1449 PATENT AND TRADEMARK OFFICE HA75-006 PRIORITY: 10/437,650 APPLICANT: Richard L. Hartman et al. LIST OF ART CITED BY APPLICANT (Use several sheets if necessary) **FILING DATE GROUP** PRIORITY: 05/13/2003 PRIORITY: 2175 U.S. PATENT DOCUMENTS Class Subclass Filing Date 'Examiner's Document Date Name If Appropriate Number initials 5.164,897 11/1992 Clark et al. 364 401 AB 5.675.507 10/1997 Bobo, II 348 14.12 AC 03/1998 709 205 5,724,508 Harple, Jr et al. AD 200.49 03/1998 Her-Hoyman et al. 395 5,727,156 AE 5,729,637 03/1998 Nicholson et al. 382 180 04/1998 707 104 Rowe et al. 5,737,599 200.3 04/1998 Scholl et al. 395 5,742,762 05/1998 Hartman et al. 705 1 5,758,324 707 513 5,781,785 07/1998 Rowe et al. FOREIGN PATENT DOCUMENTS Class Translation Country Document Date Number Yes OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.) Erin Callaway, "High-tech Hunt", Computer world, p. 115, Nov. 21, 1994. CLD Kevin Scheier, "IntelliMatch introducing newest recruitment tool since the PC", Business Wire, AN Oct. 19, 1994. AO Nebel et al., "Request for Comments: 1867", Xerox Corporation, Nov. 1995, pp. 1-13. DATE CONSIDERED 8/3/06 EXAMINED/ Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

U.S. DEPARTMENT OF COMMERCE ATTY, DOCKET NO. SERIAL NO. Form PTO-1449 PATENT AND TRADEMARK OFFICE HA75-006 PRIORITY: 10/437,650 LIST OF ART CITED BY APPLICANT APPLICANT: Richard L. Hartman et al. (Use several sheets if necessary) FILING DATE **GROUP** PRIORITY: 05/13/2003 PRIORITY: 2175 **U.S. PATENT DOCUMENTS** Date Name Subclass Filing Date \*Examiner's Document # Appropriate Initials Number CLD AA 11/1998 705 1 5,832,497 Taylor ΑĐ 707 513 5,845,299 12/1998 Arora et al. AC 395 187.01 5,892,905 04/1999 Brandt et al. ΑĐ 705 5,978,768 11/1999 McGovern et al. 1 ΑE 707 102 5,999,939 12/1999 de Hilster et al. AF AG AH AJ FOREIGN PATENT DOCUMENTS Date Country Class SubclasS Translation Document Yes No AJ AK AL OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.) "Using Restrac Scanner with Restrac Hire and Restrac Plan Release 1.2", Restrac User Manual, pp. 3-1, 1985. "Using the Recruiting Workbench, Restrac Hire 3.1", Restrac User Manual, pp. 5-2 & 6-3, 1996. AN AO 8/3/2004 DATE CONSIDERED EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.